## Supporting information

# New Fourier Transformation Method for SAXS of Polymer Lamellar Crystals 

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S1. Small-angle X-ray scatterings obtained during isothermal crystallization of iPP at $130{ }^{\circ} \mathrm{C}$


Figure S1. Scattering profiles of iPP collected during isothermal crystallization at $130{ }^{\circ} \mathrm{C}$ after removal of thermal history at $220^{\circ} \mathrm{C}$ for 5 min .

S2. Determination of form factors of a lamellar crystal and a crystal embryo at
$\theta_{i}=0^{\circ}$ and $\boldsymbol{\theta}_{i}=\mathbf{1 5}^{\circ}$
Scattering intensity of a crystal plane can be determined with following equation:
$I_{\phi}=I_{e}\left(\sum_{n=0}^{N-1} \cos n \phi\right)^{2}=\left(\frac{\sin \frac{N_{c} \phi}{2} \cos \frac{\left(N_{c}+1\right) \phi}{2}}{\sin \frac{\phi}{2}}\right)^{2} I_{e}$
where $N_{c}$ is the number of electrons on a crystalline plane, $\phi$ is the phase difference between adjacent electrons, and $I_{e}$ is the scattering intensity of a single electron. $\phi$ is determined with the following equation:

$$
\begin{equation*}
\phi=q a \sin \left(\theta_{i}-\theta\right) \tag{S2}
\end{equation*}
$$

Here $a$ is the average distance between adjacent electrons, $\theta_{i}$ is the incident angle, $\theta$ is the scattered angle. The symbol $q$ is the wave section, which is defined as:
$q=\frac{4 \pi \sin \theta}{\lambda}$

The derivation of Eq. 1 and 2 can be seen in our last study (Li et al. IUCrJ 2019, 6, 968-983). Assuming the average distance between adjacent electrons $a=0.17 \mathrm{~nm}$, the number of electrons on a crystal plane with lateral size of $l_{0}=100 \mathrm{~nm}$ is around 588 , while the number of electrons on a crystal plane with lateral size of $l_{0}=10 \mathrm{~nm}$ is around 59 . Assuming $I_{e}=1$, it can determine the scatterings of the crystal planes with $l_{0}=10 \mathrm{~nm}$ and 100 nm at $\theta_{i}=0^{\circ}$ and $15^{\circ}$ with $N_{c}$ and $a$ using Eq. S1-3. The results are shown in Figure 7b-c.

